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Search Results - Record(s) 1 through 4 of 4 returned.☐ 1. Document ID: US 20020152452 A1

L6: Entry 1 of 4

File: PGPB

Oct 17, 2002

PGPUB-DOCUMENT-NUMBER: 20020152452
PGPUB-FILING-TYPE: new
DOCUMENT-IDENTIFIER: US 20020152452 A1

TITLE: Illumination optimization for specific mask patterns

PUBLICATION-DATE: October 17, 2002

INVENTOR-INFORMATION:

NAME	CITY	STATE	COUNTRY	RULE-47
Socha, Robert John	Campbell	CA	US	

US-CL-CURRENT: 716/21; 716/19, 716/20

Full	Title	Citation	Front	Review	Classification	Date	Reference	Sequences	Attachments
Draw Desc	Image								

KMC

☐ 2. Document ID: US 20010040722 A1

L6: Entry 2 of 4

File: PGPB

Nov 15, 2001

PGPUB-DOCUMENT-NUMBER: 20010040722
PGPUB-FILING-TYPE: new
DOCUMENT-IDENTIFIER: US 20010040722 A1

TITLE: BROAD BAND DEEP ULTRAVIOLET/VACUUM ULTRAVIOLET CATADIOPTRIC IMAGING SYSTEM

PUBLICATION-DATE: November 15, 2001

INVENTOR-INFORMATION:

NAME	CITY	STATE	COUNTRY	RULE-47
SHAHER, DAVID R.	FAIRFIELD	CT	US	
CHUANG, YUNG-HO	CUPERTINO	CA	US	
ARMSTRONG, J. JOSEPH	MILIPITAS	CA	US	

US-CL-CURRENT: 359/351

Full	Title	Citation	Front	Review	Classification	Date	Reference	Sequences	Attachments
Draw Desc	Image								

KMC

☐ 3. Document ID: US 6512631 B2

L6: Entry 3 of 4

File: USPT

Jan 28, 2003

PGPUB-DOCUMENT-NUMBER: 6512631 B2
PGPUB-FILING-TYPE: new
DOCUMENT-IDENTIFIER: US 6512631 B2

TITLE: BROAD BAND DEEP ULTRAVIOLET/VACUUM ULTRAVIOLET CATADIOPTRIC IMAGING SYSTEM

PUBLICATION-DATE: January 28, 2003

INVENTOR-INFORMATION:

NAME	CITY	STATE	COUNTRY	RULE-47
SHAHER, DAVID R.	FAIRFIELD	CT	US	
CHUANG, YUNG-HO	CUPERTINO	CA	US	
ARMSTRONG, J. JOSEPH	MILIPITAS	CA	US	

US-CL-CURRENT: 359/351, 364, 365, 366, 385

WEST**Freeform Search****Database:**

US Patents Full-Text Database
US Pre-Grant Publication Full-Text Database
JPO Abstracts Database
EPO Abstracts Database
Derwent World Patents Index
IBM Technical Disclosure Bulletins

Term:

catadioptric SAME lithograph\$6 SAME inspect\$4

Display:**Documents in Display Format:****Starting with Number****Generate:** ☐ Hit List ☒ Hit Count ☐ Side by Side ☐ Image**Search****Clear****Help****Logout****Interrupt****Main Menu****Show S Numbers****Edit S Numbers****Preferences****Cases****Search History****DATE:** Sunday, May 04, 2003 [Printable Copy](#) [Create Case](#)

Set Name Query

side by side

Hit Count Set Name

result set

DB=USPT,PGPB,JPAB,EPAB,DWPI; PLUR=YES; OP=OR

<u>L15</u>	L1 & L9	10	<u>L15</u>
<u>L14</u>	L2 & L9	5	<u>L14</u>
<u>L13</u>	L3 & L9	7	<u>L13</u>
<u>L12</u>	L8 & L5	0	<u>L12</u>
<u>L11</u>	L9 & L6	0	<u>L11</u>
<u>L10</u>	L9 & L4	0	<u>L10</u>
<u>L9</u>	L5 & L7	91	<u>L9</u>
<u>L8</u>	L1 & L2 & L3	3	<u>L8</u>
<u>L7</u>	magnif\$7 SAME (detect\$4 or sens\$3) SAME inspect\$4	934	<u>L7</u>
<u>L6</u>	catadioptric SAME lithograph\$6 SAME inspect\$4	4	<u>L6</u>
<u>L5</u>	(semiconductor or wafer\$1) SAME inspect\$4 SAME (pixel\$1 or density or densities)	1001	<u>L5</u>
<u>L4</u>	catadioptric NEAR5 lens SAME (specimen or sample\$1 or object\$1) SAME inspect\$4 WITH microscop\$2	5	<u>L4</u>
<u>L3</u>	object\$3 ADJ lens SAME detect\$3 SAME field NEAR5 view\$3	541	<u>L3</u>
<u>L2</u>	detect\$3 SAME inspect\$4 SAME field NEAR5 view\$3 SAME (specimen or sample\$1 or object\$1)	195	<u>L2</u>
<u>L1</u>	microscop\$2 NEAR5 inspect\$4 SAME object\$3 ADJ lens	197	<u>L1</u>

END OF SEARCH HISTORY

US-PAT-NO: 6512631

DOCUMENT-IDENTIFIER: US 6512631 B2

TITLE: Broad-band deep ultraviolet/vacuum ultraviolet catadioptric imaging system

Full	Title	Citation	Front	Review	Classification	Date	Reference	Sequences	Attachments
Draw Desc	Image								

KWC

☐ 4. Document ID: GB 2357158 A GB 2357158 B

L6: Entry 4 of 4

File: DWPI

Jun 13, 2001

DERWENT-ACC-NO: 2002-149785

DERWENT-WEEK: 200281

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TITLE: Wafer defect inspection method, using catadioptric imaging system, involves forming multi-wavelength ultraviolet image of wafer, which is analyzed for detecting defects

Full	Title	Citation	Front	Review	Classification	Date	Reference	Sequences	Attachments
Draw Desc	Clip Img	Image							

KWC

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Terms	Documents
catadioptric SAME lithograph\$6 SAME inspect\$4	4

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WEST[Generate Collection](#)[Print](#)**Search Results - Record(s) 1 through 5 of 5 returned.**☐ 1. Document ID: US 20030076583 A1

L4: Entry 1 of 5

File: PGPB

Apr 24, 2003

PGPUB-DOCUMENT-NUMBER: 20030076583
PGPUB-FILING-TYPE: new
DOCUMENT-IDENTIFIER: US 20030076583 A1

TITLE: Ultra-broadband UV microscope imaging system with wide range zoom capability

PUBLICATION-DATE: April 24, 2003

INVENTOR-INFORMATION:

NAME	CITY	STATE	COUNTRY	RULE-47
Shafer, David R.	Fairfield	CT	US	
Chuang, Yung-Ho	Cupertino	CA	US	
Tsai, Bin-Ming B.	Saratoga	CA	US	

US-CL-CURRENT: 359/357; 359/351

Full	Title	Citation	Front	Review	Classification	Date	Reference	Sequences	Attachments
Draw Desc	Image								

KIMC

☐ 2. Document ID: US 6483638 B1

L4: Entry 2 of 5

File: USPT

Nov 19, 2002

US-PAT-NO: 6483638
DOCUMENT-IDENTIFIER: US 6483638 B1

TITLE: Ultra-broadband UV microscope imaging system with wide range zoom capability

Full	Title	Citation	Front	Review	Classification	Date	Reference	Sequences	Attachments
Draw Desc	Image								

KIMC

☐ 3. Document ID: US 6362923 B1

L4: Entry 3 of 5

File: USPT

Mar 26, 2002

US-PAT-NO: 6362923
DOCUMENT-IDENTIFIER: US 6362923 B1

TITLE: Lens for microscopic inspection

Full	Title	Citation	Front	Review	Classification	Date	Reference	Sequences	Attachments
Draw Desc	Image								

KIMC

☐ 4. Document ID: US 5999310 A

L4: Entry 4 of 5

File: USPT

Dec 7, 1999

US-PAT-NO: 5999310

DOCUMENT-IDENTIFIER: US 5999310 A

TITLE: Ultra-broadband UV microscope imaging system with wide range zoom capability

Full	Title	Citation	Front	Review	Classification	Date	Reference	Sequences	Attachments
Draw Desc	Image								

KIMC

☐ 5. Document ID: GB 2357158 A GB 2357158 B

L4: Entry 5 of 5

File: DWPI

Jun 13, 2001

DERWENT-ACC-NO: 2002-149785

DERWENT-WEEK: 200281

COPYRIGHT 2003 DERWENT INFORMATION LTD

TITLE: Wafer defect inspection method, using catadioptric imaging system, involves forming multi-wavelength ultraviolet image of wafer, which is analyzed for detecting defects

Full	Title	Citation	Front	Review	Classification	Date	Reference	Sequences	Attachments
Draw Desc	Clip Img	Image							

KIMC

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Terms	Documents
catadioptric NEAR5 lens SAME (specimen or sample\$1 or object\$1) SAME inspect\$4 WITH microscop\$2	5

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WEST**Generate Collection****Print****Search Results - Record(s) 1 through 3 of 3 returned.**☐ 1. Document ID: US 20020019003 A1

L8: Entry 1 of 3

File: PGPB

Feb 14, 2002

PGPUB-DOCUMENT-NUMBER: 20020019003
PGPUB-FILING-TYPE: new
DOCUMENT-IDENTIFIER: US 20020019003 A1

TITLE: Method for the targeted application of reagents onto immobilized biological material

PUBLICATION-DATE: February 14, 2002

INVENTOR-INFORMATION:

NAME	CITY	STATE	COUNTRY	RULE-47
Haas, Oskar A.	Kloster Neuburg		AT	
Lorch, Thomas	Reilingen		DE	
Plesch, Andreas	Schwetzingen		DE	

US-CL-CURRENT: 435/6; 382/129, 435/40.5

Full	Title	Citation	Front	Review	Classification	Date	Reference	Sequences	Attachments	Claims	RWC
Draw Desc	Image										

☐ 2. Document ID: US 6548811 B1

L8: Entry 2 of 3

File: USPT

Apr 15, 2003

US-PAT-NO: 6548811
DOCUMENT-IDENTIFIER: US 6548811 B1

TITLE: Transmission electron microscope apparatus with equipment for inspecting defects in specimen and method of inspecting defects in specimen using transmission electron microscope

Full	Title	Citation	Front	Review	Classification	Date	Reference	Sequences	Attachments	Claims	RWC
Draw Desc	Image										

☐ 3. Document ID: US 5051585 A

L8: Entry 3 of 3

File: USPT

Sep 24, 1991

US-PAT-NO: 5051585
DOCUMENT-IDENTIFIER: US 5051585 A

TITLE: Apparatus and method of pattern detection based on a scanning transmission electron microscope